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The bremsstrahlung radiation created by electron beam interactions with high atomic number scattering foils and other materials in the beam path is called photon contamination. Electrons are

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The examination of materials using electron beam techniques has developed continuously for over twenty years and there are now many different methods of extracting detailed structural and chemical information using electron beams.

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The examination of materials using electron beam techniques has developed continuously for over twenty years and there are now many different methods of extracting detailed structural and chemical information using electron beams. These techniques which include electron probe microanalysis, trans

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The primary task is sample preparation for high-resolution TEM/STEM analysis. Coupled with the in-situ electron beam induced current capabilities, this allows for extraction of specific features deemed detrimental to device performance such as grain boundaries, dislocations, and interfaces. Electron Microscopes and Material Characterization Instrumentation Clemson University Electron Microscopy Facility has some of the most-advanced electron microscopes, fostering innovation in the university's leadership in nanotechnology, toxicology, geochemistry, biological and materials research .

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Scanning Electron Microscopy (SEM) is a test process that scans a sample with an electron beam to produce a magnified image for analysis. The method is also known as SEM analysis and SEM microscopy, and is used very effectively in microanalysis and failure analysis of solid inorganic materials.

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Electron-beam processing of thermoplastic material results in an array of enhancements, such as an increase in tensile strength and resistance to abrasions, stress cracking and solvents. Joint replacements such as knees and hips are being manufactured from cross-linked ultra-high-

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